

# ICI E450 L-EFT

Pulse E-Field Source



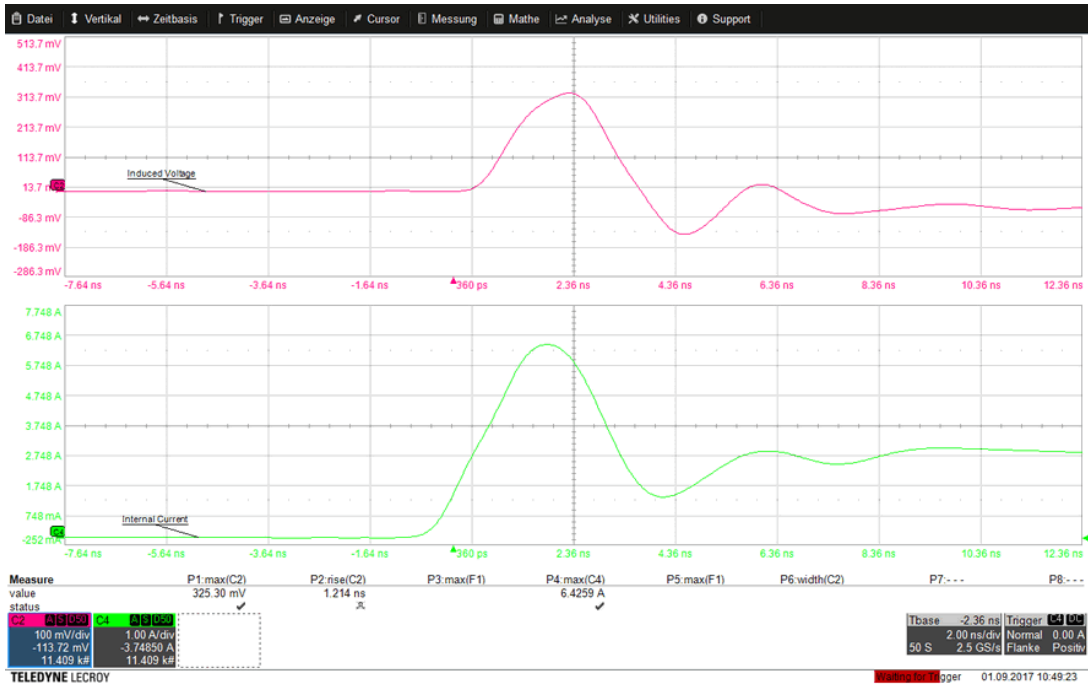
## Short description

The ICI E450 L-EFT pulse electric field source couples fast transient pulses into a test IC (open die). This allows for side channel analysis or testing the immunity of individual areas of the IC.

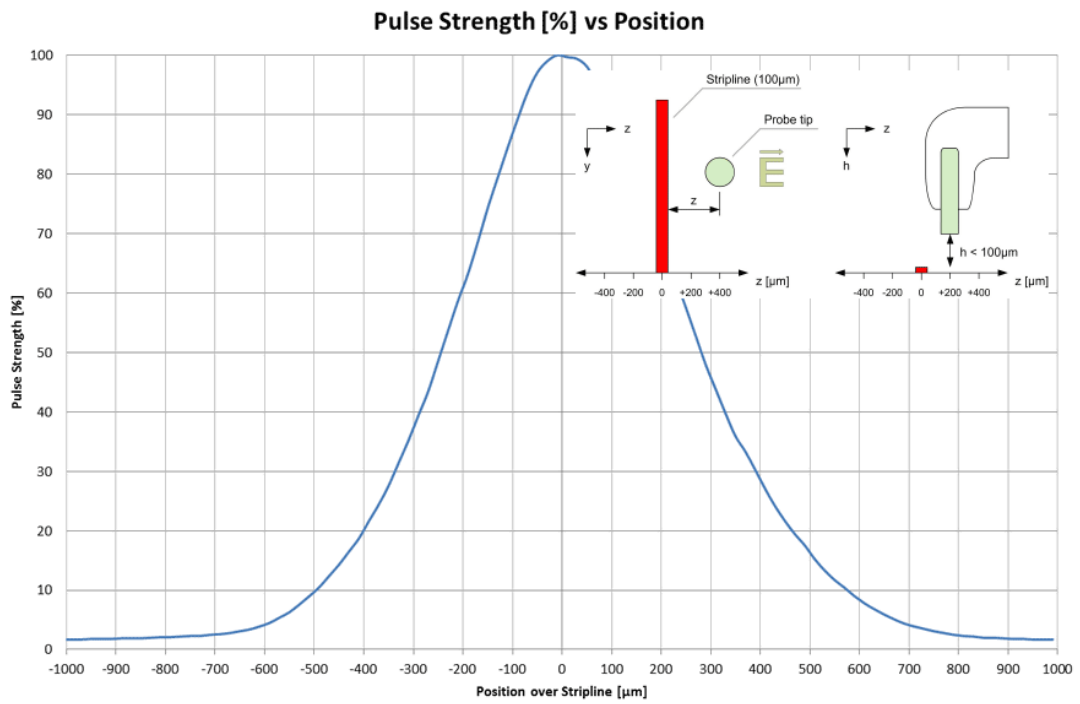
## Technical parameters

|  |                     |
|--|---------------------|
| 探头尺寸   | Ø 450 µm            |
| Max. Displacement Current (Stripline 100 µm) | 7 mA                |
| 脉冲参数   |                     |
| 上升时间   | < 2 ns              |
| 重复频率   | 0.1 Hz - 20 kHz     |
| 极性 (set by software)                         | + / - / alternating |
| 测量输出   | 50 Ω                |
| 触发器脉冲延迟 (Bypass Modus - Delay Line)          |                     |
| min. 触发器脉冲延迟 (typ.)                          | 70 ns               |
| max. 触发器脉冲延迟 (typ.)                          | 420 ns              |
| max. Jitter (typ.)                           | ± 1 ns              |
| 电源电压   | BPS 202             |
| 重量   | 70 g                |
| 尺寸 (L x W x H)                               | (26 x 43 x 53) mm   |

脉冲形状



横向扫描



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Application of ICI E450 L-EFT pulse E-field source

